

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/707,087	MAJEED ET AL.	
Examiner	Art Unit	
Brian S. Kwon	1614	

SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCH	SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR			
Updated (stn,east,npl)	9/26/2006	BK			
updated (continuity data, inventor name search)					
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